PERFORMANCE CHECKSHEET

Model: AVR-EB4-B  
Type: Semiconductor Device Tester  
S.N.: 14022  
Date: September 10, 2020  

Basic specifications: →  

Output Amplitude: to +2A, -4A  
Pulse Width (FWHM): 2 – 20 us  
Switching Time, + to -, 10%-90%: ≤ 4.5 ns  
PRF: 1 - 100 Hz  
Jitter, Stability: OK  
Prime Power: 100-240V AC, 50-60 Hz.

Test Waveforms

With an On Semi 1N4937 (date code 1832) installed in the AVX-TRR-MIX test jig, connected using the 60 cm / 24” coaxial cable:

I_F = +2A, I_R = -4A, I_{RR} = -1A.
100 Hz, 20 us PW.
5V (1A) / div, 40 ns/div.
Measured t_{RR} = 98.4 ns.

With a generic 1N4004 installed in the AVX-TRR-MIX test jig, connected using the 60 cm / 24” coaxial cable:

I_F = +2A, I_R = -4A, I_{RR} = -1A.
100 Hz, 20 us PW.
5V (1A) / div, 400 ns/div.
Measured t_{RR} = 1.07 us.
Mainframe output, with a zero Ohm jumper installed in the AVX-TRR-MIX test jig:

50 V / div, 20 ns/div. +100V, -200V.

10% - 90% fall time shown.